

an underlayer which comprises a first underlayer containing chromium as a principal component thereof, a second sputtered underlayer consisting of nickel and phosphorus and a third underlayer containing chromium as a principal component thereof which are formed in the described order,

wherein said second underlayer has a thickness of not less than 5nm, contains P in the concentration of 15 to 33 atom % in the NiP layer and has a mechanically textured structure having a surface roughness Ra_2 in a radial direction of less than 2 nm, and said third underlayer has a thickness of not more than 60 nm and has a widened lattice spacing approaching the lattice spacing of a magnetic recording layer formed thereon, and

a magnetic recording layer which has a circumferential direction of easy magnetization and contains cobalt as a principal component thereof, and also contains chromium in an amount of at least 14 at % and platinum in an amount of at least 4 at % in combination with tantalum or tantalum and niobium.

REMARKS

Attached hereto is a marked-up version of the changes made to the claims by the current amendment, captioned "Version with markings to show changes made."

Claim 1 has been amended to clarify the present invention, for reasons unrelated to patentability or a rejection, and without narrowing the claim. Support for the amendment is found on page 19, lines 4-10.